



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: TB1904-01		DATE: 29-Apr-2019	MEANS OF DISTINGUISHING CHANGED DEVICES:
Product Affected: P9242-G2NDGI P9242-G2NDGI8			☐ Product Mark ☐ Back Mark ☐ Date Code ☒ Other
Date Effective: 29-Jul-2019		Traceability to the test location is maintained by IDT and available on request	
Contact: IDT PCN DESK	Attachment: ☒ Yes ☐ No		
E-mail: pcndesk@idt.com	Samples: Please contact your local sales representative for sample request.		

DESCRIPTION AND PURPOSE OF CHANGE:

- ☐ Die Technology
- ☐ Wafer Fabrication Process
- ☐ Assembly Process
- ☐ Equipment
- ☐ Material
- ☐ Testing
- ☒ Manufacturing Site
- ☐ Data Sheet
- ☐ Other

This notification is to advise our customers that IDT is adding KYEC and ASEK, Taiwan as the alternate facilities for Test process for the selective products that are presently tested in IDT Penang, Malaysia facility.

Attachment I details the change.

RELIABILITY/QUALIFICATION SUMMARY:

There is no expected change to the product quality or reliability performance. Please refer to Attachment I for Electrical correlation data.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	☐ Approval for shipments prior to effective date.
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____

CUSTOMER COMMENTS:

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____

PRODUCT/PROCESS CHANGE NOTICE (PCN)**ATTACHMENT I - PCN # : TB1904-01**

PCN Type: Manufacturing Site - Alternate Test Locations

Data Sheet Change: None

Detail Of Change:

This notification is to advise our customers that IDT is adding KYEC and ASEK, Taiwan as alternate facilities for Test process for the selective products that are presently tested in IDT Penang, Malaysia facility.

This change will allow IDT the flexibility to ship from either facilities and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Load boards are the same at the qualified facilities. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

If you require samples to conduct evaluations, please contact your local sales representative to acknowledge this PCN and request samples.

PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT I - PCN # : TB1904-01

Qualification Information and Qualification Data:

Electrical Test Correlation Results (IDT versus KYEC)

Vehicle: P9242-G2NDGI

Sample size: 20 good and 5 reject units; 33 loop test correlation

Description	Existing Test (IDT, Penang)	Alternate Test (KYEC, Taiwan)
Tester Platform	iFLEX	iFLEX
Test Program	P9242-G2_R01	P9242-G2_R01
Test Site	Quad Site	Quad Site
Test Temperature	Ambient	Ambient
Test Correlation Results	100%	100%
Number of Good Units	20 pcs	20 pcs
20 good units datalog correlation	Passed	Passed
Number of Loop Test	33	33
4 good unit datalog correlation	Passed	Passed
Number of Reject Units	5 pcs	5 pcs
5 reject units datalog correlation	Passed	Passed

Electrical Test Correlation Results (IDT versus ASEK)

Vehicle: P9242-G2NDGI

Sample size: 20 good and 5 reject units; 33 loop test correlation

Description	Existing Test (IDT, Penang)	Alternate Test (ASEK, Taiwan)
Tester Platform	iFLEX	iFLEX
Test Program	P9242-G2_R01	P9242-G2_R01
Test Site	Quad Site	Quad Site
Test Temperature	Ambient	Ambient
Test Correlation Results	100%	100%
Number of Good Units	20 pcs	20 pcs
20 good units datalog correlation	Passed	Passed
Number of Loop Test	33	33
4 good unit datalog correlation	Passed	Passed
Number of Reject Units	5 pcs	5 pcs
5 reject units datalog correlation	Passed	Passed